



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MICRON.088DV1APPLICATION NO.
09/971,855INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT
Basceri et al.FILING DATE
October 4, 2001GROUP
2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
<i>a</i>	5,185,689	02/09/93	Maniar			
<i>ca</i>	5,406,445	04/11/95	Fujii et al.			
<i>ca</i>	5,581,436	12/03/96	Summerfelt et al.			
<i>ca</i>	5,781,404	07/14/98	Summerfelt et al.			
<i>ca</i>	5,822,175	10/13/98	Azuma			
<i>ca</i>	6,238,966	05/29/01	Ueda et al.			
<i>ca</i>	6,277,436	08/21/01	Stauf et al.			
<i>ca</i>	6,319,764	11/20/01	Basceri et al.			
<i>ca</i>	6,339,527	01/15/02	Farooq et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	

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EXAMINER

DATE CONSIDERED

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON.088DV1		APPLICATION NO. 08/971,955	
	APPLICANT Basceri et al.			
	FILING DATE October 4, 2001		GROUP 2811	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
<i>an</i>	1	6,285,051	09/04/01	Ueda et al.	257	296	
<i>an</i>	2	6,339,527	01/15/02	Farooq et al.	361	305	

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>OK</i>	3	WO95/25340	09/21/95	PCT				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
<i>an</i>	4	Joo, "Fabrication and Characterization of MOCVD (Ba, Sr)TiO ₃ Thin Films for High Density Capacitors", Proceeding of 1997 5th International Conference on VLSI and CAD, The Secretariat of ICVC '97, 1997.

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EXAMINER	<i>Se G</i>	DATE CONSIDERED	7-18-04
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			